

# PHOTORESISTS AND SPECIALTY CHEMICALS

## PERMANENT NEGATIVE PHOTORESISTS

## **Photo-patternable Epoxies**

| Product        | Description   | UV Sensitivity | Recommended<br>Film Thickness | Resolution         |
|----------------|---|----------------|-------------------------------|--------------------|
| SU-8           | Photo-definable ultra-thick structures.   | i-Line         | 25–200 μm                     | >10:1 Aspect Ratio |
| SU-8 2000      | Improved wetting.<br>Faster drying,<br>higher throughput.                         | i-Line         | 10–100 μm                     | >10:1 Aspect Ratio |
| SU-8 3000      | Improved substrate adhesion. Reduced coating stress.                              | i-Line         | 10–70 μm                      | >5:1 Aspect Ratio  |
| SU-8 TF 6000   | High resolution thin film patterning.   | g-, h-, i-Line | 0.5–10 μm                     | High Resolution    |
| KMPR® 1000     | Alkaline development. Excellent adhesion to metals & high dry etching resistance. | i-Line         | 4–75 μm                       | >5:1 Aspect Ratio  |
| PermiNex® 1000 | Wafer bonding adhesive.<br>Solvent development.                                   | i-Line         | 1–25 µm                       | 3:1 Aspect Ratio   |
| PermiNex® 2000 | Wafer bonding adhesive.<br>Alkaline development.                                  | i-Line         | 1–25 µm                       | 3:1 Aspect Ratio   |

# **Photo-patternable Specialty Polymers**

| Product    | Description  | UV Sensitivity | Recommended<br>Film Thickness | Resolution       |
|------------|--|----------------|-------------------------------|------------------|
| KMSF® 1000 | Ultra-low stress,<br>low temperature<br>cure dielectric. | Broadband      | 3–10 µm                       | 1:1 Aspect Ratio |



## **TEMPORARY RESISTS**

## **Bi-layer Lift-off Resists**

| Product      | Description   | Temperature<br>Range | Recommended<br>Film Thickness | Undercut Rate |
|--------------|---|----------------------|-------------------------------|---------------|
| PMGI SF Slow | Very high level of undercut control for high resolution thin film depositions.                              | > 180°C              | 50–800 nm                     | Very Slow     |
| PMGI SF      | High resolution thin film depositions.  | > 180°C              | 0.05–2 μm                     | Slow          |
| LOR A        | Enhanced dissolution rate for high to mid-resolution depositions. For use with 0.26N TMAH based developers. | 150-190°C            | 0.1–2.5 μm                    | Medium        |
| LOR B        | Enhanced dissolution rate for lower resolution depositions. For MIB developers.                             | 150-190°C            | 1–4 µm                        | Fast          |
| LOR C        | Excellent coverage over topography.   | 150-190°C            | 0.5–6.5 μm                    | Medium Fast   |

## **E-beam Resists**

| Product                     | Description  | Casting Solvent          | Film Thickness |
|-----------------------------|--|--------------------------|----------------|
| 950 PMMA                    | High resolution. High contrast.  | Anisole or Chlorobenzene | 0.05–5 μm      |
| 495 PMMA                    | High speed.  | Anisole or Chlorobenzene | 0.05–2.2 μm    |
| MMA (8.5) MAA<br>Copolymers | For undercut profiles in multi-layer schemes including T-gate processes. | Ethyl lactate            | 0.1–1 μm       |

## **ANCILLARIES**

# For Photoresists & Specialty Resist Products

| Developers         |
|--------------------|
| Removers           |
| Adhesion Promoters |
| Thinners           |
| Edge Bead Removers |